Essentials of MOSFETs

Unit 4: Transmission Theory of the MOSFET

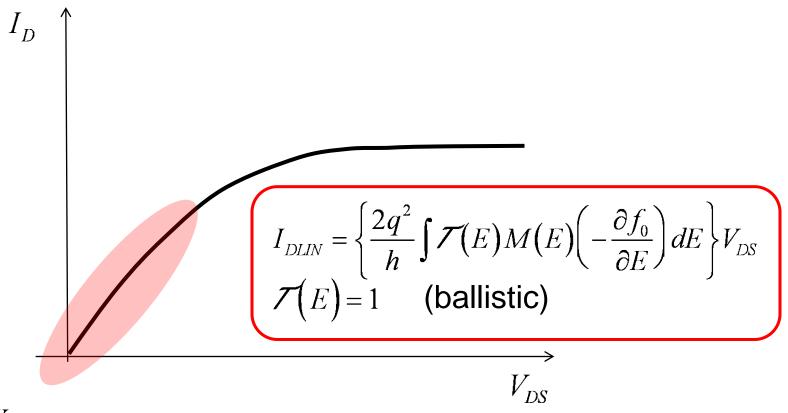
Lecture 4.3: The Ballistic MOSFET

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1) Linear region



$$I_{DLIN} = \frac{W}{L} \mu_n C_{ox} (V_{GS} - V_T) V_{DS} \rightarrow ?$$

Linear region with MB statistics (i)

$$I_{DLIN} = G_{CH}V_{DS}$$

$$G_{CH} = \frac{2q^2}{h} \int_{E_C}^{\infty} \mathcal{T}(E) M(E) \left(-\frac{\partial f_0}{\partial E}\right) dE$$

(See Sections 13.3 and 15.4 of FoN lecture notes for the complete derivation.)

$$M(E) = Wg_V \frac{\sqrt{2m^*(E - E_C)}}{\pi\hbar} \quad (2D)$$

$$\mathcal{T}(E) = 1$$

$$f_0(E) = \frac{1}{1 + e^{(E - E_F)/k_B T}} \approx e^{(E_F - E)/k_B T}$$

$$n_S = N_{2D}e^{(E_F - E_C)/k_BT}$$
 (nondegenerate)

$$N_{2D} = \left(g_V \frac{m^*}{\pi \hbar^2} k_B T \right)$$

Linear region with MB statistics (ii)

$$G_{CH} = \frac{2q^2}{h} \int_{E_C}^{\infty} \mathcal{T}(E) M(E) \left(-\frac{\partial f_0}{\partial E}\right) dE$$

$$G_{CH} = W(qn_S) \frac{\upsilon_T}{2(k_B T/q)}$$
 $\upsilon_T = \sqrt{\frac{2k_B T}{\pi m^*}}$

$$qn_S = -Q_n = C_{inv} (V_{GS} - V_T)$$

$$G_{CH} = W C_{inv} \left(V_{GS} - V_T \right) \frac{\upsilon_T}{2 \left(k_B T / q \right)}$$



$$M(E) = g_V W \frac{\sqrt{2m^*(E - E_C)}}{\pi\hbar}$$

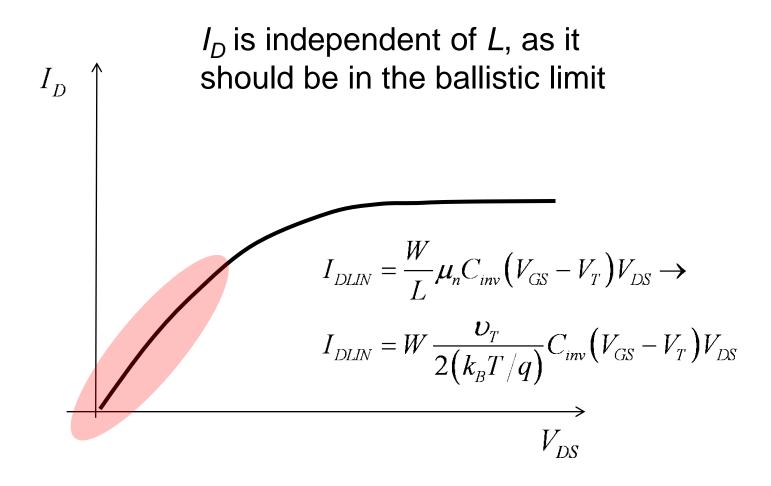
$$\mathcal{T}(E)=1$$

$$f_0(E) = e^{(E_F - E)/k_B T}$$

$$n_{S} = N_{2D}e^{(E_F - E_C)/k_BT}$$

$$N_{2D} = \left(g_V \frac{m^*}{\pi \hbar^2} k_B T \right)$$

1) Linear region

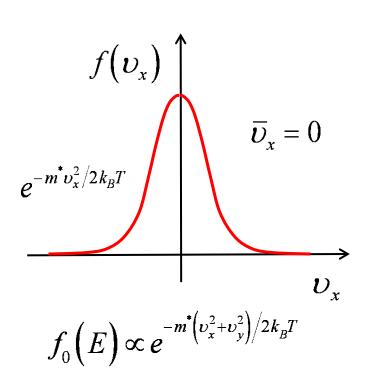


Questions

$$I_{DLIN} = W \frac{\upsilon_T}{2(k_B T/q)} C_{inv} (V_{GS} - V_T) V_{DS}$$
 $\upsilon_T = \sqrt{\frac{2k_B T}{\pi m^*}}$

- 1) How do we interpret the velocity, v_T ?
- 2) Why does the traditional model, with (W/L) times mobility fit measured data for nanoscale MOSFETs so well?

Equilibrium Maxwellian velocity distribution

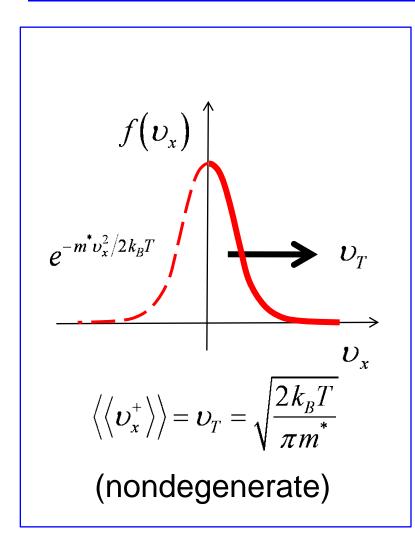


$$f_0(E) = \frac{1}{1 + e^{(E - E_F)/k_B T}} \approx e^{(E_F - E)/k_B T}$$

$$E = E_C + \frac{1}{2}m^*\upsilon^2$$

$$f_0(E) = e^{(E_F - E_C)/k_B T} \times e^{-m^* v^2/2k_B T}$$

Unidirectional thermal velocity



average over angle:

$$\langle \nu_x^+(E) \rangle = \frac{2}{\pi} \nu(E)$$
 (2D)

average over energy:

$$\left\langle \left\langle \upsilon_{x}^{+}(E)\right\rangle \right\rangle = \frac{\int_{E_{C}}^{\infty} \left\langle \upsilon_{x}^{+}(E)\right\rangle D_{2D}(E) f_{0}(E) dE}{\int_{E_{C}}^{\infty} D_{2D}(E) f_{0}(E) dE}$$

(Exercise 12.2, p. 189, of FoN)

Ballistic mobility

$$I_{DLIN} = \frac{W}{L} \mu_n C_{inv} (V_{GS} - V_T) V_{DS}$$

traditional

$$I_{DLIN} = W \left(\frac{\upsilon_{T}}{2(k_{B}T/q)} \right) C_{inv} (V_{GS} - V_{T}) V_{DS}$$

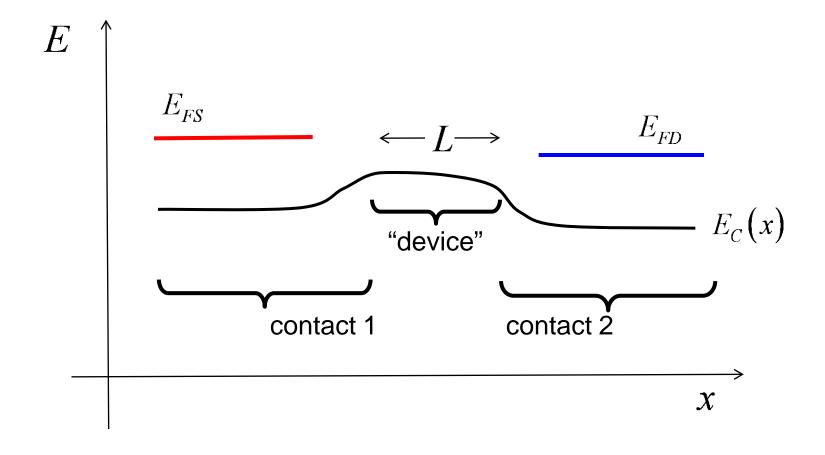
Landauer

$$I_{DLIN} = \frac{W}{L} \left(\frac{\upsilon_{T} L}{2(k_{B}T/q)} \right) C_{inv} (V_{GS} - V_{T}) V_{DS}$$

$$\mu_{\!\scriptscriptstyle B} \equiv rac{\upsilon_{\!\scriptscriptstyle T} L}{2 ig(k_{\!\scriptscriptstyle B} T/qig)}$$
 "ballistic mobility"

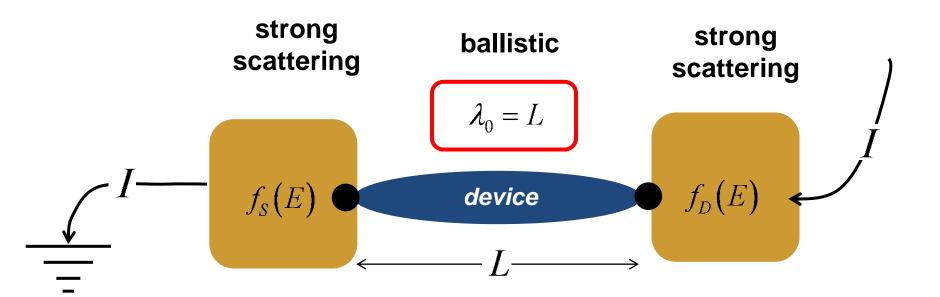
$$\mu_n = \frac{\upsilon_T \lambda_0}{2 \left(k_B T/q\right)}$$
"diffusive mobility"

Low bias energy band diagram

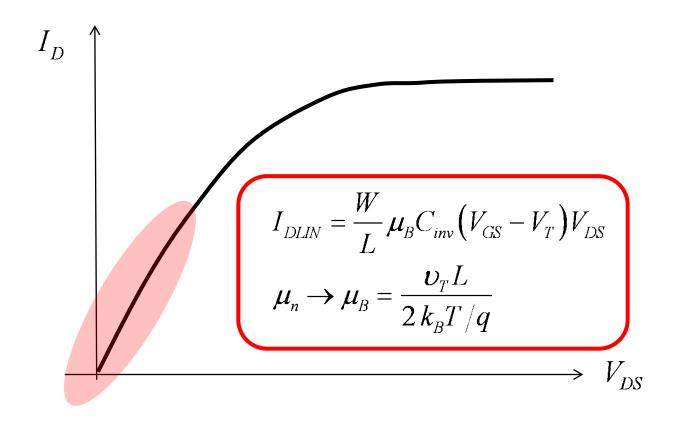


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MFP in a ballistic device

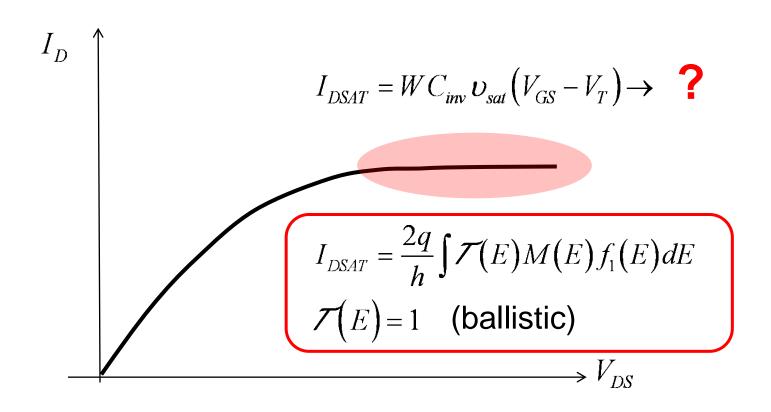


1) Linear region summary



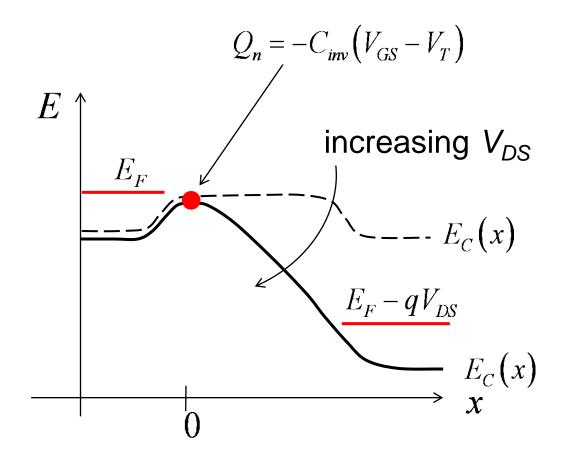
ballistic limit: μ_B diffusive limit: μ_n

2) Saturation region

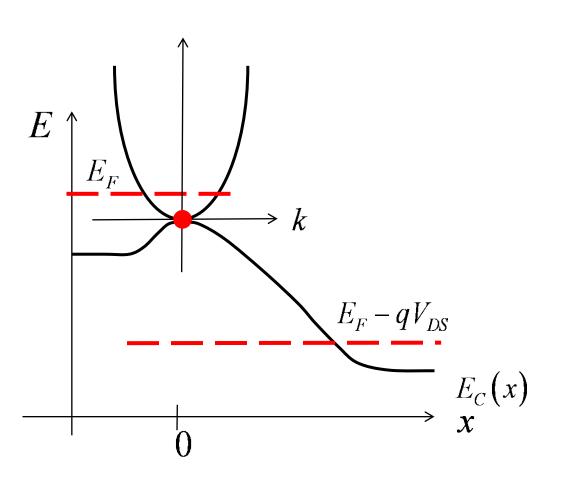


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Focus on the VS (the top of the barrier)



Electron density at the VS



$$n_S^+ = \frac{N_{2D}}{2} e^{(E_F - E_C)/k_B T}$$

$$n_{S}^{-} = \frac{N_{2D}}{2} e^{(E_{F} - qV_{DS} - E_{C})/k_{B}T} \approx 0$$

$$q(n_S^+ + n_S^-) \approx q n_S^+ = -Q_n$$

$$Q_n = -C_{inv} \left(V_{GS} - V_T \right)$$

$$qn_S^+ = C_{inv}(V_{GS} - V_T) = qn_S$$

Saturation region with MB statistics

$$I_{DSAT} = \frac{2q}{h} \int_{E_C}^{\infty} \mathcal{T}(E) M(E) f_1(E) dE$$

(See Sections 13.4 and 15.4 of FoN lecture notes for the complete derivation.)

$$M(E) = g_V W \frac{\sqrt{2m^*(E - E_C)}}{\pi\hbar}$$

$$\mathcal{T}(E)=1$$

$$f_1(E) = f_0(E) = e^{(E_F - E)/k_B T}$$

$$v_T = \sqrt{2k_BT/\pi m^*}$$

$$n_{S} = \frac{N_{2D}}{2}e^{(E_{F}-E_{C})/k_{B}T}$$

Saturation region with MB statistics

$$I_{DSAT} = \frac{2q}{h} \int_{E_C}^{\infty} \mathcal{T}(E) M(E) f_1(E) dE$$

$$I_{DSAT} = W(qn_S)\upsilon_T$$

$$qn_S = -Q_n = C_{inv} (V_{GS} - V_T)$$

$$I_{DSAT} = WC_{inv} (V_{GS} - V_T) \upsilon_T$$

$$M(E) = g_V W \frac{\sqrt{2m^*(E - E_C)}}{\pi\hbar}$$

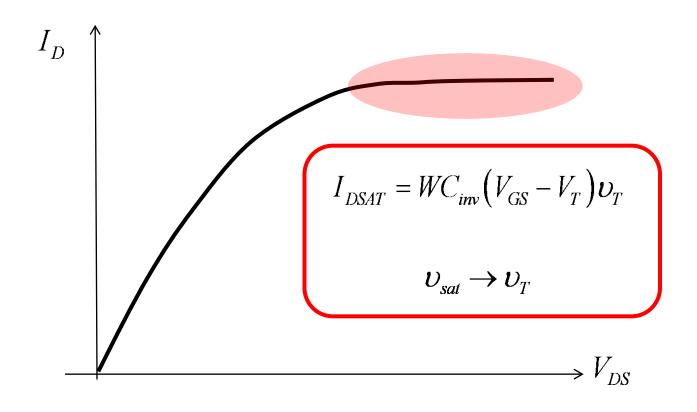
$$\mathcal{T}(E)=1$$

$$f_1(E) = f_0(E) = e^{(E_F - E)/k_B T}$$

$$\upsilon_{T} = \sqrt{2k_{B}T/\pi m^{*}}$$

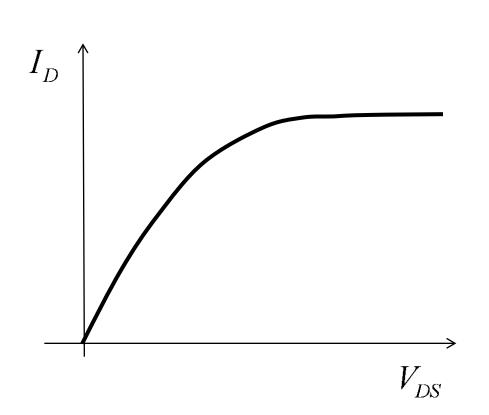
$$n_{S} = \frac{N_{2D}}{2}e^{(E_{F}-E_{C})/k_{B}T}$$

2) Saturation region summary



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3) Ballistic MOSFET: full V_{DS} range



$$I_D = \frac{2q}{h} \int \mathcal{T}(E) M(E) (f_1 - f_2) dE$$

$$I_D = I_{S \to D} - I_{D \to S}$$

$$I_{S\to D} = -W \, Q_n^+ \, \, \mathcal{O}_T$$

$$I_{D\to S} = -W Q_n^- \upsilon_T$$

$$I_D = -W \upsilon_T \left(Q_n^+ - Q_n^- \right)$$
$$= -W \upsilon_T Q_n^+ \left(1 - Q_n^- / Q_n^+ \right)$$

Full V_{DS} expression

$$I_{D} = -W \upsilon_{T} Q_{n}^{+} \left(1 - Q_{n}^{-} / Q_{n}^{+}\right)$$

$$Q_n = Q_n^+ + Q_n^- = Q_n^+ \left(1 + Q_n^- / Q_n^+ \right)$$

$$Q_{n}^{+} = \frac{Q_{n}}{\left(1 + Q_{n}^{-}/Q_{n}^{+}\right)}$$

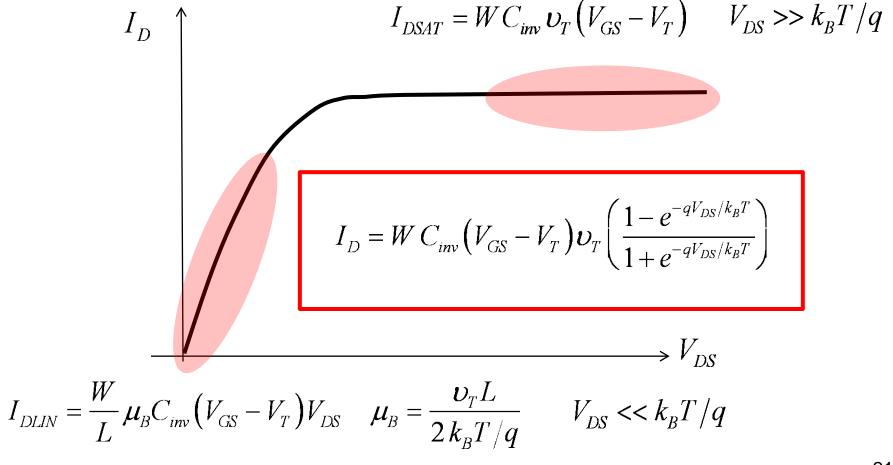
$$I_{D} = -W \upsilon_{T} Q_{n} \frac{\left(1 - Q_{n}^{-}/Q_{n}^{+}\right)}{\left(1 + Q_{n}^{-}/Q_{n}^{+}\right)}$$

$$I_{D} = W C_{inv} \left(V_{GS} - V_{T}\right) \upsilon_{T} \left(\frac{1 - e^{-qV_{DS}/k_{B}T}}{1 + e^{-qV_{DS}/k_{B}T}}\right)$$

$$\frac{Q_n^-}{Q_{-}^+} = e^{-qV_{DS}/k_BT}$$

$$I_{D} = W C_{inv} (V_{GS} - V_{T}) \upsilon_{T} \left(\frac{1 - e^{-qV_{DS}/k_{B}T}}{1 + e^{-qV_{DS}/k_{B}T}} \right)$$

Full range ballistic model (nondegenerate)



From subthreshold to above threshold

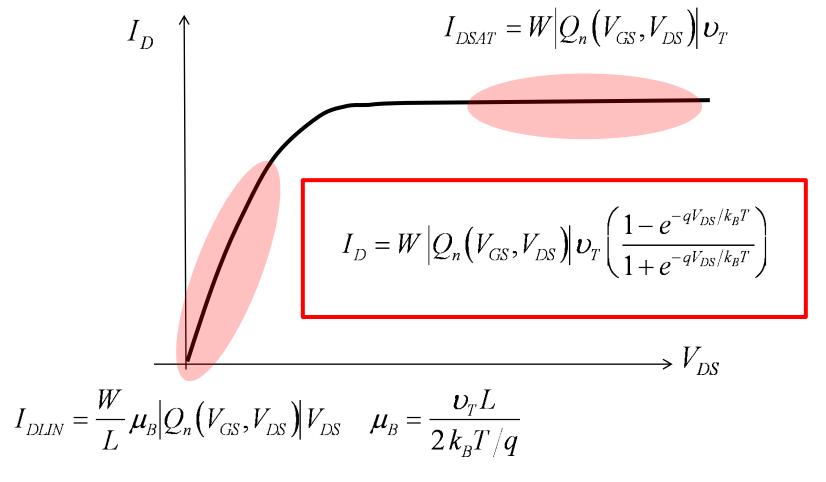
$$V_{GS} >> V_T$$

$$V_{GS} >> V_{T}$$

$$C_{inv} \left(V_{GS} - V_{T} \right) = \left| Q_{n} \left(V_{GS}, V_{DS} \right) \right|$$

$$V_T = V_{T0} - \delta V_{DS}$$

From subthreshold to above threshold



Summary

The traditional, linear region expression for I_D can be extended to the ballistic regime by replacing the mobility with the **ballistic mobility**.

The traditional, saturation region expression for I_D can be extended to the ballistic regime by replacing the high-field saturation velocity with the uni-directional thermal velocity.

Next lecture

$$I_{D} = W |Q_{n}(V_{GS}, V_{DS})| \langle \upsilon_{x}(V_{GS}, V_{DS}) \rangle$$

In the next lecture, we will examine the average velocity at the top of the barrier (the VS) vs. gate and drain bias.